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	Application No.	Applicant(s)	- Q'
Notice of Allowability	10/721,110	COBBLEY ET AL.	
	Examiner	Art Unit	
	Russell M. Kobert	2829	
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.			
1. This communication is responsive to the RCE filed 22 April 2005.			
2. The allowed claim(s) is/are 1,2 and 13-18.			
3. 🔀 The drawings filed on 10 December 2004 and 24 November 2003 are accepted by the Examiner.			
4.			
<ul> <li>Attachment(s)</li> <li>1. ☐ Notice of References Cited (PTO-892)</li> <li>2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)</li> <li>3. ☒ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 0405 &amp; 0605</li> <li>4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material</li> </ul>	5. ☐ Notice of Informal P 6. ☐ Interview Summary Paper No./Mail Da 7. ☐ Examiner's Amendr 8. ☒ Examiner's Stateme 9. ☐ Other	(PTO-413), te ment/Comment	

Application/Control Number: 10/721,110

Art Unit: 2829

Reasons for Allowance

1. The following is an examiner's statement of reasons for allowance:

A process of electrically testing a flip-chip semiconductor assembly according to the order of

sequential steps of:

(1) Directly detachably contacting a surface of a substrate with probes

(2) While the substrate is in contact with the probes, bringing a die and the substrate together

in conductive contact to form the flip-chip semiconductor assembly

(3) Electrically testing the assembly using the probes before the die is sealed

As described in claim 1 has not been found. It is further noted that the examiner's reasons are

understood to be predicated upon consideration of each of the claims as a whole, and not upon

any specific elements of the claims.

Any comments considered necessary by applicant must be submitted no later than the

payment of the issue fee and, to avoid processing delays, should preferably accompany the issue

fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for

Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Russell Kobert whose telephone number is (571) 272-1963. The Examiner's Supervisor, Nestor R. Ramirez, can be reached at (571) 272-2034. For an automated

menu of Tech Center 2800 phone numbers call (571) 272-2800.

Russell M. Kobert

Patent Examiner

Group Art Unit 2829

March 11, 2005

June 24, 2005

VINH NGUYEN PRIMARY EXAMINER

A.u. 2829

06/24/05

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